

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10541992	VAN LEEUWEN, MARCO
	Examiner	Art Unit
	keaton, sherrod	2175

SEARCHED

Class	Subclass	Date	Examiner
715	788	6-21-07	SK
715	788	12-5-07	sk
701	208, 201, 210, 213	12-5-07	sk
715	788	6-19-08	SK
701	208	6-19-08	SK
715	788	2-25-09	SK

SEARCH NOTES

Search Notes	Date	Examiner
US PGPUB & US PAT	6-21-07	SK
plus search	12-5-07	sk
US PGPUB & US PAT(715/788, 707, 208,201,210, 121,213)	12-5-07	sk
US PGPUB & US PAT(715/788, 707, 208,201,210, 121,213)	6-19-08	SK
NPL	6-19-08	SK
US PGPUB & US PAT	2-25-09	SK
INVENTOR NAME SEARCH	2-25-09	SK
NPL (IEEE)	2-25-09	SK

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner